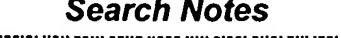


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/023,455	OHNISHI ET AL.
	<b>Examiner</b> Jan M. Ludlow	<b>Art Unit</b> 1743

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner